

Notice of References Cited	Application/Control No. 10/734,544	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner John P. Sheehan	Art Unit 1742	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0047240 A1	03-2003	Honkura et al.	148/105
*	C	US-5,858,124 A	01-1999	Endo et al.	148/302
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	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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